

Search Notes

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Jinhee J. Lee

Applicant(s)/Patent under
Reexamination

ALZNAUER ET AL.

Art Unit

2831

SEARCHED

Class	Subclass	Date	Examiner
174	152R, 152g, 360, 362	10/26/2006	LEE

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
174	as above	10/26/2006	LEE

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR